

Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits

Jenihhin, Maksim; Squillero, Giovanni; **Tihomirov, Valentin**; **Kostin, Sergei**; **Raik, Jaan**; **Ubar, Raimund-Johannes** Journal of electronic testing : theory and applications (JETTA) 2016 / p. 273-289 : ill <https://doi.org/10.1007/s10836-016-5589-x> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)